Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/681,622	CHAN ET AL.	
Examiner	**Art Unit**	
Matthew F. DeSanto	3763	

SEARCHED			
Class	Subclass	Date	Examiner
604	20, 500-503, 508, 509, 892.1	3/28/07	MFD
604	264-266	↓	↓
604	269, 523		
604	537		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
604	892.1,264	3/28/07	MFD
604	523,265	↓	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Inventor search	3/28/07	MFD